

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination MONDAL ET AL.	
		Examiner Toan M. Le	Art Unit 2863	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,768,694	07-2004	Anand et al.	365/225.7
	B	US-6,829,736	12-2004	Marinissen et al.	714/711
	C	US-6,856,569	02-2005	Nelson et al.	365/225.7
	D	US-6,728,916	04-2004	Chen et al.	714/733
	E	US-6,667,918	12-2003	Leader et al.	365/201
	F	US-6,651,202	11-2003	Phan, Tuan L.	714/733
	G	US-6,343,366	01-2002	Okitaka, Takenori	714/733
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Cowan et al., On-Chip Repair and an ATE Independent Fusing Methodology, 2002 IEEE, ITC International Test Conference, Pages 178-186
	V	Schober et al., Memory Built-In Self-Repair Using Redundant Words, 2001 IEEE, ITC International Test Conference, Pages 995-1001
	W	Tanabe et al., A 30-ns 64-Mb DRAM With Built-In Self-Test and Self-Repair Function, November 1992, IEEE Journal of Solid-State Circuits, Vol. 27, No. 11, Pages 1525-1533
	X	Treuer et al., Built-In Self-Diagnosis for Repairable Embedded RAMs, 1993 IEEE, IEEE Design & Test of Computers, Pages 24-33

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.